



CERTIFICATE OF ACCREDITATION

ANSI-ASQ National Accreditation Board

500 Montgomery Street, Suite 625, Alexandria, VA 22314, 877-344-3044

This is to certify that

Fox Valley Metrology, Ltd.
308 Axminister Drive
Fenton MO 63026

has been assessed by ANAB
and meets the requirements of international standard

ISO/IEC 17025:2005

and national standard

ANSI/NCSL Z540-1-1994 (R2002) &

ANSI/NCSL Z540.3-2006 (R2013)

while demonstrating technical competence in the fields of

TESTING AND CALIBRATION

Refer to the accompanying Scope of Accreditation for information regarding the types of calibrations and/or tests to which this accreditation applies.

ACT-1272.02

Certificate Number


ANAB Approval

Certificate Valid: 07/07/2017-06/15/2019
Version No. 001 Issued: 07/07/2017



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005,
ANSI/NCSL Z540-1-1994 (R2002), AND ANSI/NCSL Z540.3-2006 (R2013)**

Fox Valley Metrology, Ltd.
308 Axminister Drive
Fenton, MO 63026
Caleb Pohlman 636-326-1601

CALIBRATION

Valid to: **June 15, 2019**

Certificate Number: **ACT-1272.02**

Acoustics and Vibration

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Sound Level - Source ¹ 100 Hz, 250 Hz, 500 Hz, 1 000 Hz, 2 000 Hz	114 dB	0.6 dB	Gen Rad 1562-A

Chemical Quantities

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
pH Meters ¹	(4.01, 7, 10) pH	0.02 pH	pH Buffer Solutions
Conductivity Meters ¹	12.85 mS/cm 1 408 µS/cm	0.18 mS/cm 14 µS/cm	Conductivity Solutions
Refractometers ¹	(0.0, 18.0, 29.7) BRIX	0.24 BRIX	Refractive Index Solutions

Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
DC Voltage - Source ¹ Fixed Value	10 V	0.8 µV/V	Fluke 732B

Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
DC Voltage - Source ¹	Up to 220 mV 220 mV to 2.2 V (2.2 to 11) V (11 to 22) V (22 to 220) V 220 V to 1.1 kV	12 μ V/V + 0.4 μ V 5.8 μ V/V + 0.7 μ V 4.2 μ V/V + 2.5 μ V 4.1 μ V/V + 4 μ V 5.8 μ V/V + 40 μ V 7.6 μ V/V + 0.4 mV	Fluke 5720A
DC Voltage - Measure ¹	Up to 100 mV 100 mV to 1 V (1 to 10) V (10 to 100) V 100 V to 1 kV	7.8 μ V/V + 0.8 μ V 5.7 μ V/V + 0.8 μ V 5.6 μ V/V + 1 μ V 7.9 μ V/V + 80 μ V 7.9 μ V/V + 0.15 mV	Agilent 3458A Opt 002
DC High Voltage - Measure ¹	(1 to 10) kV (10 to 100) kV	60 V 0.6 kV	Hipotronics KVM-100
DC Current - Source ¹	Up to 220 μ A 220 μ A to 2.2 mA (2.2 to 22) mA (22 to 220) mA 220 mV to 2.2 A	0.12 mA/A + 6 nA 42 μ A/A + 7 nA 41 μ A/A + 40 nA 52 μ A/A + 0.7 μ A 93 μ A/A + 12 μ A	Fluke 5720A
	(2.2 to 11) A (11 to 20.5) A	0.58 mA/A + 0.5 mA 1.2 mA/A + 0.75 mA	Fluke 5520A
	(20.5 to 1 000) A	86 mA/A + 0.5 A	Fluke 5520A with 50-turn Coil
DC Current - Measure ¹	Up to 100 nA 100 nA to 1 μ A (1 to 10) μ A (10 to 100) μ A 100 μ A to 1 mA (1 to 10) mA (10 to 100) mA 100 mA to 1 A	48 μ A/A + 65 pA 35 μ A/A + 65 pA 35 μ A/A + 0.15 nA 35 μ A/A + 1.3 nA 35 μ A/A + 10 nA 36 μ A/A + 0.1 μ A 15 μ A/A + 1 μ A 0.14 mA/A + 20 μ A	Agilent 3458A Opt 002
DC Current - Measure ¹	(1 to 10) A	2.4 mA/A + 0.7 mA	Fluke DMM



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Resistance - Source ¹	0 Ω	0.11 mΩ	Fluke 5720A
	1 Ω	0.11 mΩ	
	1.9 Ω	0.21 mΩ	
	10 Ω	0.27 mΩ	
	19 Ω	0.51 mΩ	
	100 Ω	1.4 mΩ	
	190 Ω	2.6 mΩ	
	1 kΩ 1.9 kΩ	11 mΩ 21 mΩ	
Resistance - Source ¹	10 kΩ	0.11 Ω	Fluke 5720A
	19 kΩ	0.21 Ω	
	100 kΩ	1.3 Ω	
	190 kΩ	2.7 Ω	
	1 MΩ	24 Ω	
	1.9 MΩ	48 Ω	
	10 MΩ	0.48 kΩ	
	19 MΩ	1.1 kΩ	
	100 MΩ	23 kΩ	IET Labs HRRS Decade Box
	1 GΩ	1.9 MΩ	
10 GΩ 100 GΩ	47 MΩ 0.95 GΩ		
Resistance - Measure ¹	Up to 10 Ω	24 μΩ/Ω + 0.1 mΩ	Agilent 3458A Opt 002
	(10 to 100) Ω	20 μΩ/Ω + 1 mΩ	
	100 Ω to 1 kΩ	18 μΩ/Ω + 1 mΩ	
	(1 to 10) kΩ	18 μΩ/Ω + 10 mΩ	
	(10 to 100) kΩ	18 μΩ/Ω + 0.1 Ω	
	100 kΩ to 1 MΩ	24 μΩ/Ω + 7 mΩ	
	(1 to 10) MΩ	87 μΩ/Ω + 0.2 Ω	
	(10 to 100) MΩ 100 MΩ to 1 GΩ	0.73 mΩ/Ω + 2 Ω 7.2 mΩ/Ω + 20 kΩ	



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Voltage - Source ¹	Up to 2.2 mV		Fluke 5720A
	(10 to 20) Hz	2.4 mV/V + 4 μV	
	(20 to 40) Hz	2.4 mV/V + 4 μV	
	40 Hz to 20 kHz	2.2 mV/V + 4 μV	
	(20 to 50) kHz	2.2 mV/V + 4 μV	
	(50 to 100) kHz	2.3 mV/V + 5 μV	
	(100 to 300) kHz	2.5 mV/V + 10 μV	
	(300 to 500) kHz	2.7 mV/V + 20 μV	
	500 kHz to 1 MHz	3.8 mV/V + 20 μV	
	(2.2 to 22) mV		
	(10 to 20) Hz	0.61 mV/V + 4 μV	
	(20 to 40) Hz	0.56 mV/V + 4 μV	
	40 Hz to 20 kHz	0.36 mV/V + 4 μV	
	(20 to 50) kHz	0.42 mV/V + 4 μV	
	(50 to 100) kHz	0.70 mV/V + 5 μV	
	(100 to 300) kHz	1.3 mV/V + 10 μV	
	(300 to 500) kHz	1.7 mV/V + 20 μV	
	500 kHz to 1 MHz	3.4 mV/V + 20 μV	
	(22 to 220) mV		
	(10 to 20) Hz	0.29 mV/V + 12 μV	
	(20 to 40) Hz	0.13 mV/V + 7 μV	
	40 Hz to 20 kHz	0.11 mV/V + 7 μV	
	(20 to 50) kHz	0.24 mV/V + 7 μV	
	(50 to 100) kHz	0.54 mV/V + 17 μV	
	(100 to 300) kHz	1.1 mV/V + 20 μV	
	(300 to 500) kHz	1.6 mV/V + 25 μV	
	500 kHz to 1 MHz	3.3 mV/V + 45 μV	
	(0.22 to 2.2) V		
	(10 to 20) Hz	0.28 mV/V + 40 μV	
	(20 to 40) Hz	0.11 mV/V + 15 μV	
	40 Hz to 20 kHz	55 μV/V + 8 μV	
	(20 to 50) kHz	0.12 mV/V + 10 μV	
	(50 to 100) kHz	0.13 mV/V + 30 μV	
	(100 to 300) kHz	0.49 mV/V + 80 μV	
	(300 to 500) kHz	1.2 mV/V + 0.2 mV	
	500 kHz to 1 MHz	2.0 mV/V + 0.3 mV	



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Voltage - Source ¹	(2.2 to 22) V (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz	0.28 mV/V + 0.2 mV 0.11 mV/V + 0.15 mV 56 μV/V + 50 μV 0.12 mV/V + 0.1 mV 0.12 mV/V + 0.2 mV 0.32 mV/V + 0.6 mV 1.2 mV/V + 2 mV 1.8 mV/V + 3.2 mV	Fluke 5720A
	(22 to 220) V (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz 220 V to 1.1 kV (15 to 50) Hz 50 Hz to 1 kHz	0.28 mV/V + 4 mV 0.11 mV/V + 1.5 mV 65 μV/V + 0.6 mV 0.12 mV/V + 1 mV 0.18 mV/V + 2.5 mV 1.1 mV/V + 16 mV 5.1 mV/V + 40 mV 9.3 mV/V + 80 mV 0.35 mV/V + 16 mV 88 μV/V + 3.5 mV	
AC Voltage Harmonics – Source (2 nd to 50 th) ¹ (10 to 45) Hz (45 to 65) Hz (65 to 500) Hz 500 Hz to 5 kHz (5 to 10) kHz	32 mV to 33 V 33 mV to 1 kV 33 mV to 1 kV 330 mV to 1 kV 3.3 V to 1 kV	0.35 mV/V + 16 μV 0.21 mV/V + 16 μV 0.21 mV/V + 16 μV 0.21 mV/V + 0.21 mV 0.21 mV/V + 1.2 mV	Fluke 5520A
AC Voltage - Measure ¹ Bandwidth < 2 MHz	Up to 10 mV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (10 to 100) mV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 2) MHz	0.46 mV/V + 13 μV 0.35 mV/V + 11 μV 0.46 mV/V + 11 μV 1.3 mV/V + 11 μV 5.9 mV/V + 11 μV 46 μV/V + 12 μV 0.14 mV/V + 4.5 μV 0.14 mV/V + 2.5 μV 0.22 mV/V + 2.5 μV 0.41 mV/V + 2.5 μV 0.99 mV/V + 2.5 μV 3.5 mV/V + 11 μV 12 mV/V + 11 μV 18 mV/V + 11 μV	Agilent 3458A Opt 002



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Voltage - Measure ¹ Bandwidth < 2 MHz	100 mV to 1 V		Agilent 3458A Opt 002
	(1 to 40) Hz	0.14 mV/V + 45 μV	
	40 Hz to 1 kHz	0.14 mV/V + 25 μV	
	(1 to 20) kHz	0.22 mV/V + 25 μV	
	(20 to 50) kHz	0.41 mV/V + 25 μV	
	(50 to 100) kHz	0.99 mV/V + 25 μV	
	(100 to 300) kHz	3.5 mV/V + 0.11 mV	
	300 kHz to 1 MHz	12 mV/V + 0.11 mV	
	(1 to 2) MHz	18 mV/V + 0.11 mV	
	(1 to 10) V		
	(1 to 40) Hz	0.14 mV/V + 0.45 mV	
	40 Hz to 1 kHz	0.14 mV/V + 0.25 mV	
	(1 to 20) kHz	0.22 mV/V + 0.25 mV	
	(20 to 50) kHz	0.41 mV/V + 0.25 mV	
	(50 to 100) kHz	0.98 mV/V + 0.25 mV	
	(100 to 300) kHz	3.5 mV/V + 1.1 mV	
	300 kHz to 1 MHz	12 mV/V + 1.1 mV	
	(1 to 2) MHz	18 mV/V + 1.1 mV	
	(10 to 100) V		
	(1 to 40) Hz	0.29 mV/V + 4.5 mV	
40 Hz to 1 kHz	0.29 mV/V + 2.5 mV		
(1 to 20) kHz	0.29 mV/V + 2.5 mV		
(20 to 50) kHz	0.29 mV/V + 2.5 mV		
(50 to 100) kHz	1.5 mV/V + 2.5 mV		
(100 to 300) kHz	4.7 mV/V + 11 mV		
300 kHz to 1 MHz	18 mV/V + 11 mV		
100 V to 1 kV			
(1 to 40) Hz	0.52 mV/V + 45 mV		
40 Hz to 1 kHz	0.52 mV/V + 25 mV		
(1 to 20) kHz	0.75 mV/V + 25 mV		
(20 to 50) kHz	1.5 mV/V + 25 mV		
(50 to 100) kHz	3.5 mV/V + 25 mV		
(1 to 10) kV		Hipotronics KVM-100	
(50 to 60) Hz	0.12 kV		
(10 to 100) kV			
(50 to 60) Hz	1.2 kV		



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Voltage - Measure ¹ Bandwidth > 2 MHz	Up to 10 mV		Agilent 3458A Opt 002
	45 Hz to 100 kHz	1.2 mV/V + 6 μV	
	100 kHz to 1 MHz	14 mV/V + 5.1 μV	
	(1 to 4) MHz	83 mV/V + 7.1 μV	
	(4 to 8) MHz	0.24 V/V + 8.1 μV	
	(10 to 100) mV		
	45 Hz to 100 kHz	1.1 mV/V + 61 μV	
	100 kHz to 1 MHz	24 mV/V + 51 μV	
	(1 to 4) MHz	47 mV/V + 71 μV	
	(4 to 8) MHz	47 mV/V + 81 μV	
	(8 to 10) MHz	0.18 V/V + 0.1 mV	
	100 mV to 1 V		
45 Hz to 100 kHz	1.1 mV/V + 0.61 mV		
100 kHz to 1 MHz	24 mV/V + 0.51 mV		
(1 to 4) MHz	47 mV/V + 0.71 mV		
(4 to 8) MHz	47 mV/V + 0.81 mV		
(8 to 10) MHz	0.18 V/V + 1 mV		
(1 to 10) V			
45 Hz to 100 kHz	1.2 mV/V + 6.1 μV		
100 kHz to 1 MHz	24 mV/V + 5.1 μV		
(1 to 4) MHz	47 mV/V + 7.1 μV		
(4 to 8) MHz	47 mV/V + 8.1 μV		
(8 to 10) MHz	0.18 V/V + 10 μV		
AC Voltage - Measure ¹ Bandwidth > 2 MHz	(10 to 100) V		Hipotronics KVM-100
	45 Hz to 100 kHz	1.5 mV/V + 2.5 mV	
	100 V to 1 kV		
	45 Hz to 100 kHz	3.6 mV/V + 0.11 V	
AC Current - Source ¹	Up to 220 μA		Fluke 5720A
	(10 to 20) Hz	0.30 mA/A + 16 nA	
	(20 to 40) Hz	0.20 mA/A + 10 nA	
	40 Hz to 1 kHz	0.16 mA/A + 8 nA	
	(1 to 5) kHz	0.22 mA/A + 12 nA	
	(5 to 10) kHz	1.3 mA/A + 65 nA	
	220 μA to 2.2 mA		
	(10 to 20) Hz	0.31 mA/A + 40 nA	
	(20 to 40) Hz	0.22 mA/A + 35 nA	
	40 Hz to 1 kHz	0.15 mA/A + 35 nA	
	(1 to 5) kHz	0.24 mA/A + 0.11 μA	
	(5 to 10) kHz	1.3 mA/A + 0.65 μA	



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Current - Source ¹	(2.2 to 22) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (22 to 220) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz 220 mA to 2.2 A 20 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (2 to 3) A (10 to 45) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.32 mA/A + 0.4 μA 0.23 mA/A + 0.35 μA 0.15 mA/A + 0.35 μA 0.24 mA/A + 0.55 μA 1.3 mA/A + 5 μA 0.30 mA/A + 4 μA 0.20 mA/A + 3.5 μA 0.15 mA/A + 2.5 μA 0.24 mA/A + 3.5 μA 1.3 mA/A + 10 μA 0.31 mA/A + 35 μA 0.53 mA/A + 80 μA 8.1 mA/A + 0.16 mA 2.1 mA/A + 0.1 mA 0.75 mA/A + 0.1 mA 6.9 mA/A + 1 mA 29 mA/A + 5 mA	Fluke 5720A
AC Current - Source ¹	(3 to 11) A (45 to 100) Hz (0.1 to 1) kHz (1 to 5) kHz (11 to 20.5) A (45 to 100) Hz (0.1 to 1) kHz (1 to 5) kHz	0.74 mA/A + 2 mA 1.2 mA/A + 2 mA 35 mA/A + 2 mA 1.4 mA/A + 5 mA 1.8 mA/A + 5 mA 35 mA/A + 5 mA	Fluke 5520A
AC Current - Source ¹	(20.5 to 1 000) A (45 to 65) Hz (20.5 to 150) A (65 to 440) Hz	90 mA/A + 0.5 A 0.55 mA/A + 0.5 mA	Fluke 5520A w/ 50-turn Coil
AC Current Harmonics - Source ¹ (2 nd to 50 th)	(10 to 45) Hz (45 to 65) Hz (65 to 500) Hz 500 Hz to 5 kHz (5 to 10) kHz 3.3 mA to 3 A 3.3 mA to 20.5 A 33 mA to 20.5 A 33 mA to 20.5 A (33 to 330) mA	1.1 mA/A + 4 μA 0.5 mA/A + 4 μA 1.2 mA/A + 0.1 mA 2.3 mA/A + 0.2 mA 4.6 mA/A + 0.4 mA	Fluke 5520A

Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
AC Current - Measure ¹	Up to 100 μ A (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz 100 μ A to 1 mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz (1 to 10) mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz	4.8 mA/A + 30 nA 1.9 mA/A + 30 nA 0.83 mA/A + 30 nA 0.83 mA/A + 30 nA 4.9 mA/A + 0.2 μ A 1.9 mA/A + 0.2 μ A 0.83 mA/A + 0.2 μ A 0.47 mA/A + 0.2 μ A 0.83 mA/A + 0.2 μ A 4.9 mA/A + 0.4 μ A 6.6 mA/A + 1.5 μ A 4.9 mA/A + 2 μ A 1.9 mA/A + 2 μ A 0.83 mA/A + 2 μ A 0.47 mA/A + 2 μ A 0.83 mA/A + 2 μ A 4.9 mA/A + 4 μ A 6.6 mA/A + 15 μ A	Agilent 3458A Opt 002
AC Current - Measure ¹	(10 to 100) mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz 100 mA to 1 A (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz	4.9 mA/A + 20 μ A 1.9 mA/A + 20 μ A 0.83 mA/A + 20 μ A 0.47 mA/A + 20 μ A 0.47 mA/A + 20 μ A 4.9 mA/A + 40 μ A 6.6 mA/A + 0.15 mA 4.8 mA/A + 0.2 mA 2 mA/A + 0.2 mA 1.1 mA/A + 0.2 mA 1.3 mA/A + 0.2 mA 3.7 mA/A + 0.2 mA 12 mA/A + 0.4 mA	Agilent 3458A Opt 002
AC Current - Measure ¹	(1 to 10) A (20 to 50) Hz 50 Hz to 2 kHz	0.23 A/A + 10 mA 36 mA/A + 10 mA	Fluke DMM
Capacitance - Measure ¹ 42 Hz to 5 MHz	0.32 pF to 370 mF	1.1 mF/F	Hioki 3532-50



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Capacitance - Source ¹	130 pF to 3.3 nF (3.3 to 11) nF (11 to 110) nF (110 to 330) nF 330 nF to 1.1 μF (1.1 to 3.3) μF (3.3 to 11) μF (11 to 33) μF (33 to 110) μF (110 to 330) μF 330 μF to 1.1 mF (1.1 to 3.3) mF (3.3 to 11) mF (11 to 33) mF (33 to 110) mF	5.8 mF/F + 10 pF 2.9 mF/F + 10 pF 2.9 mF/F + 0.1 nF 2.9 mF/F + 0.3 nF 2.9 mF/F + 1 nF 2.9 mF/F + 3 nF 2.9 mF/F + 10 nF 4.7 mF/F + 30 nF 5.3 mF/F + 0.1 μF 1 mF/F + 0.3 μF 6 mF/F + 1 μF 5.3 mF/F + 3 μF 5.3 mF/F + 10 μF 8.9 mF/F + 30 μF 13 mF/F + 0.1 mF	Fluke 5520A
Phase - Measure ¹	(0 to 360) ° 10 Hz to 2 kHz (2 to 5) kHz (5 to 10) kHz (10 to 50) kHz (50 to 60) kHz (60 to 70) kHz	0.026 ° 0.036 ° 0.048 ° 0.059 ° 0.07 ° 0.082 °	Clark Hess 6000A
Phase - Measure ¹	(0 to 360) ° (70 to 80) kHz (80 to 90) kHz (90 to 100) kHz (100 to 500) kHz 500 kHz to 1 MHz	0.093 ° 0.1 ° 0.12 ° 0.58 ° 1.2 °	Clark Hess 6000A
DC Power - Source ¹	10 mW to 330 W 330 W to 3 kW (3 to 20.5) kW	0.27 mW/W 0.26 mW/W 0.82 mW/W	Fluke 5520A
AC Power - Source ¹	100 μW to 9 W (9 to 33) W (33 to 90) W (90 to 330) W (330 to 900) W 900 W to 2.2 kW	1.7 mW/W 1.2 mW/W 1.7 mW/W 1.2 mW/W 11 mW/W 4.6 mW/W	Fluke 5520A



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment	
Oscilloscopes ¹				
DC Voltage (50 Ω)	1 mV to 6.6 V	2.9 mV/V + 40 μV	Fluke 5520A SC1100	
DC Voltage (1 MΩ)	1 mV to 130 V	0.55 mV/V + 40 μV		
AC Voltage (50 Ω)	1 mV to 6.6 V	2.9 mV/V + 40 μV		
AC Voltage (1 MΩ)	1 mV to 130 V	1.1 mV/V + 40 μV		
Leveled Sine Wave 50 kHz to 1.1 GHz	5 mV to 5.5 V	51 mV/V + 0.1 mV		
Time Markers	1 ns to 5 s	6.4 μs/s		
Wave Generator (50 Ω)	1.8 mV to 2.5 V p-p	35 mV/V + 0.10 mV		
Wave Generator (1 MΩ)	1.8 mV to 55 V p-p	35 mV/V + 0.10 mV		
Pulse Generator - Width	(4 to 45) nS (45 to 500) nS	58 mS/S + 0.5 ns 58 mS/S + 4 ns		
Pulse Generator - Period	200 ns to 20 mS	58 mS/S + 0.2 μs		
Input Impedance Measure	(50 to 60) Ω 500 kΩ to 1 MΩ	1.2 mΩ/Ω 1.2 mΩ/Ω		
Electrical Simulation of RTDs ¹	Pt 385, 100 Ω (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (500 to 630) °C (630 to 800) °C Pt 3926, 100 Ω (-200 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (500 to 630) °C	0.05 °C 0.05 °C 0.07 °C 0.09 °C 0.10 °C 0.12 °C 0.23 °C 0.05 °C 0.05 °C 0.07 °C 0.09 °C 0.10 °C 0.12 °C		Fluke 5520A



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Electrical Simulation of RTDs ¹	Pt 3916 (JIS) 100 Ω		Fluke 5520A
	(-200 to -190) °C	0.25 °C	
	(-190 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.07 °C	
	(300 to 400) °C	0.09 °C	
	(400 to 600) °C	0.10 °C	
	(600 to 630) °C	0.23 °C	
	Pt 385, 200 Ω		
	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.04 °C	
	(0 to 100) °C	0.04 °C	
	(100 to 260) °C	0.05 °C	
	(260 to 300) °C	0.12 °C	
	(300 to 400) °C	0.13 °C	
	(400 to 600) °C	0.14 °C	
	(600 to 630) °C	0.16 °C	
	Pt 385, 500 Ω		
	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.08 °C	
	(300 to 400) °C	0.08 °C	
	(400 to 600) °C	0.09 °C	
	(600 to 630) °C	0.11 °C	
	Pt 385, 1 000 Ω		
	(-200 to -80) °C	0.03 °C	
	(-80 to 0) °C	0.03 °C	
(0 to 100) °C	0.04 °C		
(100 to 260) °C	0.05 °C		
(260 to 300) °C	0.06 °C		
(300 to 400) °C	0.07 °C		
(400 to 600) °C	0.07 °C		
(600 to 630) °C	0.23 °C		
PtNi 385, 120 Ω, Ni 120			
(-80 to 0) °C	0.08 °C		
(0 to 100) °C	0.08 °C		
(100 to 260) °C	0.14 °C		
Cu 427, 10 Ω			
(-100 to 260) °C	0.03 °C		



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Electrical Simulation of Thermocouples ¹	Type K		Fluke 5520A
	(-200 to -100) °C	0.33 °C	
	(-100 to -25) °C	0.18 °C	
	(-25 to 120) °C	0.16 °C	
	(120 to 1 000) °C	0.26 °C	
	(1 000 to 1 372) °C	0.40 °C	
	Type J		
	(-210 to -100) °C	0.27 °C	
	(-100 to -30) °C	0.16 °C	
	(-30 to 150) °C	0.14 °C	
	(150 to 760) °C	0.17 °C	
	(760 to 1 200) °C	0.23 °C	
	Type E		
	(-250 to -100) °C	0.50 °C	
	(-100 to -35) °C	0.16 °C	
	(-25 to 350) °C	0.14 °C	
	(350 to 650) °C	0.16 °C	
	(650 to 1 000) °C	0.21 °C	
	Type T		
	(-250 to -150) °C	0.63 °C	
	(-150 to 0) °C	0.24 °C	
	(0 to 120) °C	0.16 °C	
	(120 to 400) °C	0.14 °C	
	Type S		
	(0 to 250) °C	0.47 °C	
	(250 to 1 000) °C	0.36 °C	
	(1 000 to 1400) °C	0.37 °C	
	(1 400 to 1 767) °C	0.46 °C	
Type B			
(600 to 800) °C	0.44 °C		
(-100 to -25) °C	0.34 °C		
(-25 to 120) °C	0.30 °C		
(120 to 1 000) °C	0.33 °C		
Type C			
(0 to 150) °C	0.30 °C		
(150 to 650) °C	0.26 °C		
(650 to 1 000) °C	0.31 °C		
(1 000 to 1 800) °C	0.50 °C		
(1 800 to 2316) °C	0.84 °C		
Type L			
(-200 to -100) °C	0.37 °C		
(-100 to 800) °C	0.26 °C		
(800 to 900) °C	0.17 °C		



Electrical – DC/Low Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Electrical Simulation of Thermocouples ¹	Type N		Fluke 5520A
	(-200 to -100) °C	0.40 °C	
	(-100 to -25) °C	0.22 °C	
	(-25 to 120) °C	0.19 °C	
	(120 to 410) °C	0.18 °C	
	(410 to 1300) °C	0.27 °C	
	Type R		
	(0 to 250) °C	0.57 °C	
	(250 to 400) °C	0.35 °C	
	(400 to 1 000) °C	0.33 °C	
(1 000 to 1 767) °C	0.40 °C		
Type U			
(-200 to 0) °C	0.56 °C		
(0 to 600) °C	0.27 °C		
Inductance - Source ¹	(1 to 10) mH	22 mH/H	General Radio 1490-D
	(10 to 100) mH	11 mH/H	
	100 mH to 1 H	6 mH/H	
	(1 to 10) H	3 mH/H	
Ionizers ¹ Decay Time Float Voltage	(0.1 to 999.9) s	0.2 s	Trek 156A
	(-1 100 to 1 100) V	3.1 V	

Electrical - RF/Microwave

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
RF Power – Measure ^{1,4} Absolute Level 100 kHz to 3 GHz (3 to 18) GHz (18 to 26.5) GHz 100 kHz to 3 GHz (3 to 18) GHz (18 to 26.5) GHz	(+20 to +30) dBm	0.37 dB	Agilent N5531S Measuring Receiver with N5532A Sensor Modules
		0.39 dB	
		0.4 dB	
	(-20 to +20) dBm	0.15 dB	
		0.18 dB	
		0.21 dB	

Electrical - RF/Microwave

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Relative Level (3.05 to 6.6) GHz (6.6 to 13.2) GHz (13.2 to 19.2) GHz (19.2 to 26.5) GHz	 (-90 to +30) dBm (-113 to -90) dBm (-81 to +30) dBm (-104 to -81) dBm (-70 to +30) dBm (-93 to -70) dBm (-62 to +30) dBm (-85 to -62) dBm	 0.026 dB + 0.005 dB/10 dB 0.067 dB + 0.12 dB/10 dB 0.026 dB + 0.005 dB/10 dB 0.062 dB + 0.12 dB/10 dB 0.026 dB + 0.005 dB/10 dB 0.056 dB + 0.12 dB/10 dB 0.026 dB + 0.005 dB/10 dB 0.051 dB + 0.12 dB/10 dB	 Agilent N5531S Measuring Receiver with N5532A Sensor Modules
Amplitude Modulation - Source ^{1,4} Rate: DC to 100 kHz Depths: 0 % to 100 %	250 kHz to 40 GHz	7.1 % of setting + 1 %	Agilent E8257D
Amplitude Modulation - Measure ^{1,4} 100 kHz to 10 MHz 10 MHz to 3 GHz 10 MHz to 3 GHz (3 to 26.5) GHz (3 to 26.5) GHz	 Rate: 50 Hz to 10 kHz Depths: 5 % to 99 % Rate: 50 Hz to 100 kHz Depths: 20 % to 99 % Rate: 50 Hz to 100 kHz Depths: 5 % to 20 % Rate: 50 Hz to 100 kHz Depths: 20 % to 99 % Rate: 50 Hz to 100 kHz Depths: 5 % to 20 %	 2.2 % of reading 1.2 % of reading 4.2 % of reading 3.5 % of reading 6 % of reading	 Agilent N5531S Measuring Receiver with N5532A Sensor Modules
Phase Modulation - Source ^{1,4} Rate: DC to 100 kHz	250 kHz to 40 GHz	5.9 % setting + 0.1 rad	Agilent E8257D



Electrical - RF/Microwave

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Tuned RF Level - Measure ^{1,4} Absolute Level 500 kHz to 3.05 GHz (3.05 to 6.6) GHz (6.6 to 13.2) GHz (13.2 to 19.2) GHz (19.2 to 26.5) GHz	(+16 to +30) dBm	0.37 dB + 0.005 dB/10 dB	Agilent N5531S Measuring Receiver with N5532A Sensor Modules
	(-106 to +16) dBm	0.15 dB + 0.005 dB/10 dB	
	(-129 to -106) dBm	0.15 dB + 0.12 dB/10 dB	
	(+20 to +30) dBm	0.39 dB + 0.005 dB/10 dB	
	(-90 to +20) dBm	0.18 dB + 0.005 dB/10 dB	
	(-114 to -90) dBm	0.23 dB + 0.12 dB/10 dB	
	(+20 to +30) dBm	0.39 dB + 0.005 dB/10 dB	
	(-81 to +20) dBm	0.18 dB + 0.005 dB/10 dB	
	(-104 to -81) dBm	0.23 dB + 0.12 dB/10 dB	
	(+20 to +30) dBm	0.4 dB + 0.005 dB/10 dB	
	(-70 to +20) dBm	0.21 dB + 0.005 dB/10 dB	
	(-93 to -70) dBm	0.25 dB + 0.12 dB/10 dB	
	(+20 to +30) dBm	0.4 dB + 0.005 dB/10 dB	
	(-62 to +20) dBm	0.21 dB + 0.005 dB/10 dB	
	(-85 to -62) dBm	0.24 dB + 0.12 dB/10 dB	
Tuned RF Level - Measure ^{1,4} Relative Level 500 kHz to 3.05 GHz	(-90 to +30) dBm	0.026 dB + 0.005 dB/10 dB	Agilent N5531S Measuring Receiver with N5532A Sensor Modules
	(-106 to -90) dBm	0.067 dB + 0.12 dB/10 dB	
	(-129 to -106) dBm	0.076 dB + 0.12 dB/10 dB	
RF Power - Source ¹ 250 kHz to 2 GHz (2 to 20) GHz (20 to 40) GHz	> -10 dBm	0.72 dB 0.96 dB 1.1 dB	Agilent E8257D
250 kHz to 2 GHz (2 to 20) GHz (20 to 40) GHz	(-10 to -70) dBm	0.89 dB 1.1 dB 1.2 dB	
250 kHz to 2 GHz (2 to 20) GHz (20 to 40) GHz	(-70 to -90) dBm	0.95 dB 1.2 dB 1.21 dB	



Electrical - RF/Microwave

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
RF Power Sensors- Calibration Factor ^{1,4} 100 kHz to 10 MHz 10 MHz to 10 GHz (10 to 18) GHz	(-20 to +14) dBm	1.5 % 1.5 % 1.7 %	Tegam 1827, Agilent 3458A, Agilent E8257D, Agilent E4419B, Agilent 3325B
Frequency Modulation - Measure ^{1,4} 250 kHz to 10 MHz 10 MHz to 3 GHz (3 to 26.5) GHz	Rate: 20 Hz to 10 kHz Dev.: ≤ 40 kHz peak Rate: 20 Hz to 200 kHz Dev.: ≤ 400 kHz peak Rate: 20 Hz to 200 kHz Dev.: ≤ 400 kHz peak	3.1 % of reading 3.1 % of reading 7.7 % of reading	Agilent N5531S Measuring Receiver with N5532A Sensor Modules
Frequency Modulation - Source ^{1,4} 250 kHz to 40 GHz	1 dB Rate: DC to 100 kHz 3 dB Rate: DC to 10 MHz Dev: ≤ (N X 800 kHz)	4.2 % setting + 20 Hz	Agilent E8257D
Pulse Generation - Measure ^{1,4} DC to 225 MHz Pulse Width Rise/Fall Time	5 ns to 10 ⁵ S 5 ns to 10 ⁵ S	1.1 nS 1.1 nS	Agilent 53132A
Pulse Generation - Source ^{1,4} Repetition Frequency: 0.024 Hz to 14.28 MHz Period: 70 ns to 42 s	10 ns to 42 s	17 ns	Agilent E8257D

Length – Dimensional Metrology

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Gage Blocks ² Per ASME B89.1.9	Up to 10 in (10 to 20) in Up to 20 in	(3.9 + 1.3L) μin (8.5 + 1L) μin (3.9 + 1.3L) μin	LabMaster Universal ULM 600 Mahr 828
Length Standards ²	Up to 9 in (9 to 24) in (24 to 70) in	(39 + 0.4L) μin (12 + 1L) μin (390 + 2.6L) μin	P&W Supermicrometer ULM 600 CMM



Length – Dimensional Metrology

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Cylindrical Rings ²	(0.25 to 8) in (0.025 to 12) in	(13 + 1.3D) μin (13 + 1.8D) μin	LabMaster Universal ULM 600 ASME B89.1.6
Cylindrical Rings ^{1,2}	(0.25 to 5) in	(12 + 3D) μin	Fowler Lab Concept ASME B89.1.6
Cylindrical Plugs ²	(0.010 to 8) in	(2.7 + 6D) μin	LabMaster Universal
Cylindrical Plugs ^{1,2}	(0.010 to 4) in	(53 + 0.4D) μin	Plug gage Comparator
Thread Rings ² Pitch Diameter Pitch Diameter Minor Diameter	Up to 8 in Up to 8 in Up to 8 in	(240 + 0.3D) μin 38 μin 120 μin	Setting Plug Gages ULM 600 ID Bore Gages ASME B1.2
NPT Rings Standoff and Basic Length	(0.062 5 to 6) in	250 μin	NPT Plugs, P&W LabMaster ASME B1.20.5
NPT Plugs Standoff and Basic Length	(0.062 5 to 6) in	490 μin	NPT Rings, P&W LabMaster ASME B1.20.5
Tapered Thread Gages ^{1,2}	(0.25 to 5) in	(53 + 6.2D) μin	Universal Supermicrometer ASME B1.20.5
Threaded Plugs ² Pitch Diameter Major Diameter	(0.01 to 10) in (0.01 to 10) in	(73 + 0.9D) μin (40 + 1.2D) μin	P&W Supermicrometer, Thread Measuring Wires ASME B1.2
Threaded Plugs ^{1,2} Pitch Diameter Major Diameter	(0.01 to 4) in (0.01 to 4) in	(73 + 3.2D) μin (53 + 4.1D) μin	Plug gage Comparator
Calipers ^{1,2}	Up to 80 in	(380 + 15L) μin	Gage Blocks
Indicators ^{1,2}	Up to 4 in	(36 + 10L) μin	Indicator Checker
Test Indicators ¹	Up to 0.06 in	39 μin	Indicator Checker
OD Micrometers ^{1,2}	Up to 60 in	(72 + 12L) μin	Gage Blocks
ID Micrometer ^{1,2}	(1.5 to 40) in	(370 + 7L) μin	Gage Blocks
Height Gages ^{1,2}	Up to 40 in	(96 + 14L) μin	Gage Blocks
Bore Gages ¹	(0.25 to 12) in	350 μin	Cylindrical Rings



Length – Dimensional Metrology

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Crimpers ¹ Die Check Crimp Height	(0.011 to 0.5) in (0.01 to 0.5) in	230 μin 0.001 2 in	Pin Gages Micrometer
Profilometers ¹ Ra	(2 to 300) μin	2.2 μin	Roughness Specimen
Surface Plates ^{1,2} Repeat Reading Overall Flatness	(4 to 34) in <i>DL</i> (34 to 175) in <i>DL</i>	(30 + 0.2 <i>DL</i>) μin (66 + 0.2 <i>DL</i>) μin	Repeat – O – Meter Electronic Levels
Optical Comparators ^{1,2} Linearity Magnification	Up to 12 in 10x, 20x, 31.25x, 50x, 62.5x, 100x, 200x	(97 + 12 <i>L</i>) μin 0.000 46 in	Glass Scale Precision Balls Calibration Sphere
Roundness Testers ^{1,2} Axial Error Radial Error	(-1 000 to 1 000) μm	0.15 μm 0.15 μm	Test Sphere
ULMs ^{1,2} Length	(1 to 100) mm	0.19 μm	Gage Blocks
Film Thickness Gages ¹	(0.01 to 0.06) in	380 μin	Film Thickness Standards
Brinell Scopes ¹	(1 to 6) mm	11 μm	Stage Micrometer

Mass

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Bench and Floor Scales ¹	Up to 120 lb Up to 5 000 lb	0.000 7 lb/lb	NIST 105 Class F Weights NIST Handbook 44
Analytical Balances ¹	Up to 13 kg	0.19 μg/g	ASTM E617 Class 1 Weights NIST Handbook 44
Pressure ¹	(-13 to 300) psi (300 to 1 000) psi	0.1 psi 1.3 psi	Pressure Calibrator
	(1 000 to 10 000) psi (10 000 to 30 000) psi	3.9 psi 35 psi	Pressure Transducers



Mass

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Direct Verification per ASTM D2240 of Durometers ¹	Up to 100 duro	0.35 duro	Durometer Calibrator
Spring Force	(0.1 to 45) N	0.05 N	Triple Beam Balance,
Indenter Angle	(20 to 40) °	0.07 °	Video Measuring Machine
Indenter Length	(0.049 to 0.198) in	330 μin	Gage Blocks
Indenter Radius	(0.05 to 0.1) in	340 μin	
Indirect Verification per ASTM E18 of Rockwell Hardness Testers ¹	HRA Low	1.2 HRA	Rockwell Test Blocks
	HRA Med	1.2 HRA	
	HRA High	0.75 HRA	
	HRBW Low	1.4 HRBW	
	HRBW Med	1.4 HRBW	
	HRBW High	1.3 HRBW	
	HRC Low	1.2 HRC	
	HRC Med	1.2 HRC	
	HRC High	0.7 HRC	
	HRE Low	1.3 HRE	
	HRE Med	1.4 HRE	
	HRE High	1.4 HRE	
	HRF Low	1.4 HRF	
	HRF Med	1.4 HRF	
	HRF High	1.4 HRF	
	HRH Low	1.4 HRH	
	HRH Med	1.4 HRH	
	HRH High	1.4 HRH	
	HRKW Low	1.4 HRKW	
	HRKW Med	1.3 HRKW	
	HRKW High	1.3 HRKW	
HRMW Low	1.4 HRMW		
HRMW Med	1.4 HRMW		
HRMW High	1.3 HRMW		



Mass

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Indirect Verification per ASTM E18 of Rockwell Superficial Hardness Testers ¹	HR15N Low	1.5 HR15N	Rockwell Test Blocks
	HR15N Med	1.3 HR15N	
	HR15N High	0.9 HR15N	
	HR30N Low	1.3 HR30N	
	HR30N Med	1.3 HR30N	
	HR30N High	0.9 HR30N	
	HR45N Low	1.4 HR45N	
	HR45N Med	1.3 HR45N	
	HR45N High	0.95 HR45N	
Indirect Verification per ASTM E18 of Rockwell Superficial Hardness Testers ¹	HR15TW Low	2 HR15TW	Rockwell Test Blocks
	HR15TW Med	1.4 HR15TW	
	HR15TW High	1.5 HR15TW	
	HR30TW Low	2 HR30TW	
	HR30TW Med	1.5 HR30TW	
	HR30T High	1.3 HR30TW	
	HR45TW Low	2.0 HR45TW	
	HR45TW Med	1.3 HR45TW	
	HR45TW High	1.4 HR45TW	
Force ¹	(0.001 to 200) lb	0.05 % of reading	Dead Weight Load Cell Load Cell
	(200 to 10 000) lb	0.07 % of reading	
	(10 000 to 50 000) lb	0.1 % of reading	
Force	1 g to 500 lb	0.05 % reading	Dead Weight, Proving Ring
	(500 to 1 000) lb	0.03 % reading	
	(1 000 to 10 000) lb	0.03 % reading	
	(10 000 to 100 000) lb	0.04 % reading	
Torque Tools ¹	4 lbf-in to 2 000 lbf-ft	0.3 % of reading	CDI Torque System
Viscosity Rotational Viscometers	500 cP 5 000 cP	0.02 cP/cP	Viscosity Solutions, Temperature Bath
Viscosity Cups	17.82 cP 65.28 cP 231 cP	0.03 cP/cP	Viscosity Solutions, Temperature Bath, Stopwatch ASTM D4212



Photometry and Radiometry

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Optical Power - Measure ¹ (800 to 1 650) nm	(+20 to -70) dBm	0.03 dB/dBm	Agilent 81533B, 81525A
Optical Power - Source ¹ (820, 1 310, 1 550) nm	(0 to -60) dB	0.05 dB/dB	Agilent 81554SM, 81533B, 81525A, 81655A, 81570A, and 81578A
Optical Attenuation - Source ¹ (700 to 1 650) nm	(0 to -60) dB	0.04 dB/dB	Agilent 81570A and 81578A
Optical Wavelength - Measure ¹	(700 to 1 650) nm	0.05 nm	Agilent 86120B

Thermodynamic

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Immersion Probes ¹	(-95 to 140) °C	0.03 °C	Fluke 9190A with PRT
Temperature - Measure ¹	(-30 to 600) °C	0.03 °C	Hart Scientific 1502 with PRT
System Accuracy Test ¹ (SAT)	(0 to 2 200) °F	2.6 °F	Certified Thermocouple
Temperature Uniformity Survey ¹ (TUS)	(0 to 2 200) °F	4.9 °F	MV 1000 Data Logger or Equivalent

Time and Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Time Interval ¹	(1 to 86 400) s	0.000 45 s	Agilent 53132A & Spectracom 8197B
Frequency Measure ¹	0.1 Hz to 225 MHz	6.7 parts in 10 ⁻¹¹ Hz	Agilent 53132A, SRS FS725
	0.1 Hz to 26.5 GHz	6.7 parts in 10 ⁻¹¹ Hz	Agilent N5531S, SRS FS725
Frequency Source ¹	10 MHz	6.7 parts in 10 ⁻¹¹ Hz	SRS FS725
	0.1 mHz to 40 GHz	6.7 parts in 10 ⁻¹¹ Hz	Agilent 3325B, Agilent E8257D, SRS FS725



Time and Frequency

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Tachometers ¹ Contact Non-Contact	(1 to 6 500) rpm (500 to 40 000) rpm	0.08 % of reading	King Nutronics 3711-B
Tachometers ¹ Non-Contact	(0.01 to 100 000) rpm	0.005 % of reading	Fluke 5520A

TESTING

Dimensional

Specific Tests and / or Properties Measured	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Dimensional Inspection Volumetric Linear	Up to (28 x 40 x 24) in Up to (28 x 40 x 24) in	320 μin (38 + 5.2L) μin	CMM CMM
Surface Finish (Ra)	(0.01 to 300) μin	2.1 μin	Profilometer

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope
2. This scope is formatted as part of a single document including Certificate of Accreditation No. ACT-1272.02.


Vice President

